

ISO/IEC JTC 1/SC 17			
Cards and personal identification			
Secretariat: BSI (United Kingdom)			
Document type:	Text for FPDAM ballot or comment		
Title:	Notification of ballot: ISO/IEC 14443-2:2010/FPDAM 4.3 - Identification cards - Contactless integrated circuit cards - Proximity cards - Part 2: Radio frequency power and signal interface - AMENDMENT 4 Additional PICC classes		
Status:	BACKWARD POINTER: N 3680, N 3744, N 3834, N 3901, N 3958, N 4000, N 4038 and N 4082.		
	<b>STATUS:</b> This ballot has been posted to the ISO Electronic balloting application and is available under the Balloting Portal, Committee Internal Balloting.		
	WORK ITEM: 54563		
Date of document:	2010-11-17		
Expected action:	VOTE		
Action due date:	2010-03-18		
Email of secretary:	<u>chris.starr@ukpayments.org.uk</u>		
Committee URL:	http://isotc.iso.org/livelink/livelink/open/jtc1sc17		

## **ISO/IEC JTC 1/SC 17**

Date: 2010-09-30

## ISO/IEC 14443-2:2010/FPDAM 4.3

ISO/IEC JTC 1/SC 17/WG 8

Secretariat: DIN

# Identification cards — Contactless integrated circuit cards — Proximity cards — Part 2: Radio frequency power and signal interface

AMENDMENT 4 Additional PICC classes

Cartes d'identification — Cartes à circuit intégré sans contact — Cartes de proximité — Partie 2: Interface radio fréquence

AMENDEMENT 4 Classes de PICC additionnelles

#### Warning

This document is not an ISO International Standard. It is distributed for review and comment. It is subject to change without notice and may not be referred to as an International Standard.

Recipients of this draft are invited to submit, with their comments, notification of any relevant patent rights of which they are aware and to provide supporting documentation.

Document type: International Standard Document subtype: Amendment Document stage: (40) Enquiry Document language: E

### **Copyright notice**

This ISO document is a Draft International Standard and is copyright-protected by ISO. Except as permitted under the applicable laws of the user's country, neither this ISO draft nor any extract from it may be reproduced, stored in a retrieval system or transmitted in any form or by any means, electronic, photocopying, recording or otherwise, without prior written permission being secured.

Requests for permission to reproduce should be addressed to either ISO at the address below or ISO's member body in the country of the requester.

ISO copyright office Case postale 56 • CH-1211 Geneva 20 Tel. + 41 22 749 01 11 Fax + 41 22 749 09 47 E-mail copyright@iso.org Web www.iso.org

Reproduction may be subject to royalty payments or a licensing agreement.

Violators may be prosecuted.

## Foreword

ISO (the International Organization for Standardization) and IEC (the International Electrotechnical Commission) form the specialized system for worldwide standardization. National bodies that are members of ISO or IEC participate in the development of International Standards through technical committees established by the respective organization to deal with particular fields of technical activity. ISO and IEC technical committees collaborate in fields of mutual interest. Other international organizations, governmental and non-governmental, in liaison with ISO and IEC, also take part in the work. In the field of information technology, ISO and IEC have established a joint technical committee, ISO/IEC JTC 1.

International Standards are drafted in accordance with the rules given in the ISO/IEC Directives, Part 2.

The main task of the joint technical committee is to prepare International Standards. Draft International Standards adopted by the joint technical committee are circulated to national bodies for voting. Publication as an International Standard requires approval by at least 75 % of the national bodies casting a vote.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO and IEC shall not be held responsible for identifying any or all such patent rights.

Amendment 4 to ISO/IEC 14443-2:2010 was prepared by Joint Technical Committee ISO/IEC JTC 1, *Information technology*, Subcommittee SC 17, *Cards and personal identification*.

## Identification cards — Contactless integrated circuit cards — Proximity cards — Part 2: Radio frequency power and signal interface

AMENDMENT 4: Additional PICC classes

Page 3 of ISO/IEC 14443-2:2010, Clause 4

Add the following symbol definitions:

*V*<sub>LMA. PCD</sub> Minimum load modulation amplitude for PCD reception

 $V_{\text{LMA, PICC}}$  Minimum load modulation amplitude for PICC transmission

Page 4 of ISO/IEC 14443-2:2010, Clause 6

Replace 6.2 by the following subclause:

#### 6.2 Operating field strength

The PCD shall generate a field strength of at least  $H_{min}$  and not exceeding  $H_{max}$  at manufacturer specified positions (operating volume) under unmodulated conditions.

The PCD

- shall support PICCs of "Class 1", "Class 2" and "Class 3";
- may optionally support PICCs of "Class 4";
- may optionally support PICCs of "Class 5";
- and may optionally support PICCs of "Class 6".

PCD requirements measured with Reference PICCs 1, 2 and 3 are mandatory for all PCDs.

PCD requirements measured with Reference PICC 4 are only mandatory for PCDs supporting operation with "Class 4" PICCs.

PCD requirements measured with Reference PICC 5 are only mandatory for PCDs supporting operation with "Class 5" PICCs.

PCD requirements measured with Reference PICC 6 are only mandatory for PCDs supporting operation with "Class 6" PICCs.

	PCD	
	<b>H</b> <sub>min</sub>	<b>H</b> <sub>max</sub>
Measured with Reference PICC 1	1,5 A/m (rms)	7,5 A/m (rms)
Measured with Reference PICC 2	1,5 A/m (rms)	8,5 A/m (rms)
Measured with Reference PICC 3	1,5 A/m (rms)	8,5 A/m (rms)
Measured with Reference PICC 4 (optional)	2,0 A/m (rms)	12 A/m (rms)
Measured with Reference PICC 5 (optional)	2,5 A/m (rms)	14 A/m (rms)
Measured with Reference PICC 6 (optional)	4,5 A/m (rms)	18 A/m (rms)

#### Table 1 — PCD field strength

The PCD shall not generate a field strength higher than the values specified for all mandatory and optional classes in ISO/IEC 14443-1:2008/Amd.1:2010, 4.4 (alternating magnetic field) in any possible PICC position and orientation, measured with the associated Reference PICCs.

Test methods for the PCD operating field are defined in ISO/IEC 10373-6 and use a dedicated Reference PICC for each class.

NOTE 1 Although field measurements with some Reference PICCs may show values higher than 7,5 A/m (rms), the new  $H_{max}$  limits specified in Table 1 do not allow PCDs to produce higher field strength than with first edition of ISO/IEC 14443-2. This is because PCD field distribution is usually not homogenous within the operating volume and References PICCs have different measurement areas.

If the PICC meets the requirements of one particular class as specified in ISO/IEC 14443-1:2008/Amd.1:2010, then the PICC shall operate as intended continuously between  $H_{min}$  and  $H_{max}$  defined for its class; this includes all PICC requirements defined in this standard and processing of the manufacturer specified set of commands.

If the PICC does not claim to meet the requirements of one particular class as specified in ISO/IEC 14443-1:2008/Amd.1:2010, then:

- if the PICC antenna fits within the external rectangle defined in "Class 2" as specified in ISO/IEC 14443-1:2008/Amd.1:2010, then:
  - the PICC shall operate as intended continuously between  $H_{min}$  and  $H_{max}$  defined for "Class 2",
  - the PICC shall pass the loading effect test defined for "Class 2";
- if the PICC antenna fits within the external rectangle or external circle defined in "Class 3" as specified in ISO/IEC 14443-1:2008/Amd.1:2010, then:
  - the PICC shall operate as intended continuously between  $H_{min}$  and  $H_{max}$  defined for "Class 3",
  - the PICC shall pass the loading effect test defined for "Class 3";
- if the PICC antenna does not claim to fit within the external rectangle or external circle defined in "Class 2" or "Class 3" as specified in ISO/IEC 14443-1:2008/Amd.1:2010, then:
  - the PICC shall operate as intended continuously between  $H_{min}$  and  $H_{max}$  defined for "Class 1",
  - the PICC shall pass the loading effect test defined for "Class 1".

NOTE 2 If the PICC does not claim to meet the requirements of one particular class then the requirements defined above may not be sufficient to guarantee proper operation and interoperability with PCDs.

	PICC	
	<b>H</b> <sub>min</sub>	H <sub>max</sub>
"Class 1" PICC	1,5 A/m (rms)	7,5 A/m (rms)
"Class 2" PICC	1,5 A/m (rms)	8,5 A/m (rms)
"Class 3" PICC	1,5 A/m (rms)	8,5 A/m (rms)
"Class 4" PICC	2,0 A/m (rms)	12 A/m (rms)
"Class 5" PICC	2,5 A/m (rms)	14 A/m (rms)
"Class 6" PICC	4,5 A/m (rms)	18 A/m (rms)

Table 2 —	- PICC	operating	field	strength
-----------	--------	-----------	-------	----------

NOTE 3 Margins of field strength are effectively included by the test methods as specified in ISO/IEC 10373-6.

#### Page 15 of ISO/IEC 14443-2:2010, 8.2

Replace 8.2.2 by the following subclause and renumber all subsequent tables:

#### 8.2.2 Load modulation

The PICC shall be capable of communication to the PCD via an inductive coupling area where the carrier frequency is loaded to generate a subcarrier with frequency *fs*. The subcarrier shall be generated by switching a load in the PICC.

If the PICC meets the requirements of one particular class as specified in ISO/IEC 14443-1:2008/Amd.1:2010, then the load modulation amplitude  $V_{LMA}$  of the PICC shall be at least  $V_{LMA, PICC}$  specified for its class when measured as described in ISO/IEC 10373-6, using the test PCD assembly defined for its class, where *H* is the value of magnetic field strength in A/m (rms).

If the PICC does not claim to meet the requirements of one particular class as specified in ISO/IEC 14443-1:2008/Amd.1:2010, then the load modulation amplitude  $V_{LMA}$  of the PICC shall be at least  $V_{LMA, PICC}$  specified for "Class 1" when measured as described in ISO/IEC 10373-6, using the test PCD assembly defined for "Class 1", where *H* is the value of magnetic field strength in A/m (rms).

Table 8 specifies for each PICC class both the load modulation amplitude limit  $V_{\text{LMA, PICC}}$  and the relevant test PCD assembly to measure the PICC load modulation amplitude  $V_{\text{LMA}}$ .

	PICC		
	VLMA, PICC	Test PCD assembly	
"Class 1" PICC	22/ <i>H</i> <sup>0,5</sup> [mV (peak)]	Test PCD assembly 1	
"Class 2" PICC	Min(14 ; 22/H <sup>0,5</sup> ) [mV (peak)]	Test PCD assembly 1	
"Class 3" PICC	Min(14 ; 22/H <sup>0,5</sup> ) [mV (peak)]	Test PCD assembly 1	
"Class 4" PICC	Min(18 ; 40/ <i>H</i> <sup>0,5</sup> ) [mV (peak)]	Test PCD assembly 2	
"Class 5" PICC	Min(14 ; 34/ <i>H</i> <sup>0,5</sup> ) [mV (peak)]	Test PCD assembly 2	
"Class 6" PICC	Min(7 ; 26/H <sup>0,5</sup> ) [mV (peak)]	Test PCD assembly 2	

#### Table 8 — PICC load modulation amplitude limit

The PCD shall be able to receive a  $V_{LMA}$  of at least  $V_{LMA, PCD}$  when measured as described in ISO/IEC 10373-6, using test PCD assembly 1, with Reference PICCs 1, 2 and 3, where *H* is the value of magnetic field strength in A/m (rms).

If the PCD supports operation with "Class 4" PICCs, it shall be able to receive a  $V_{\text{LMA}}$  of at least  $V_{\text{LMA, PCD}}$  when measured as described in ISO/IEC 10373-6, using test PCD assembly 2, with Reference PICC 4, where *H* is the value of magnetic field strength in A/m (rms).

If the PCD supports operation with "Class 5" PICCs, it shall be able to receive a  $V_{\text{LMA}}$  of at least  $V_{\text{LMA, PCD}}$  when measured as described in ISO/IEC 10373-6, using test PCD assembly 2, with Reference PICC 5, where *H* is the value of magnetic field strength in A/m (rms).

If the PCD supports operation with "Class 6" PICCs, it shall be able to receive a  $V_{LMA}$  of at least  $V_{LMA, PCD}$  when measured as described in ISO/IEC 10373-6, using test PCD assembly 2, with Reference PICC 6, where *H* is the value of magnetic field strength in A/m (rms).

Table 9 specifies for each Reference PICC both the load modulation reception limit  $V_{\text{LMA, PCD}}$  and the test PCD assembly to use to measure the PCD sensitivity.

	PCD	
	V <sub>LMA, PCD</sub>	Test PCD assembly
Measured with Reference PICC 1	20/ <i>H</i> <sup>0,5</sup> [mV (peak)]	Test PCD assembly 1
Measured with Reference PICC 2	Min(12,5 ; 20/ <i>H</i> <sup>0,5</sup> ) [mV (peak)]	Test PCD assembly 1
Measured with Reference PICC 3	Min(12,5 ; 20/ <i>H</i> <sup>0,5</sup> ) [mV (peak)]	Test PCD assembly 1
Measured with Reference PICC 4 (optional)	Min(16 ; 36/ <i>H</i> <sup>0,5</sup> ) [mV (peak)]	Test PCD assembly 2
Measured with Reference PICC 5 (optional)	Min(13 ; 31/H <sup>0,5</sup> ) [mV (peak)]	Test PCD assembly 2
Measured with Reference PICC 6 (optional)	Min(6 ; 23/ <i>H</i> <sup>0,5</sup> ) [mV (peak)]	Test PCD assembly 2

#### Table 9 — PCD load modulation reception limit

NOTE 1 The PICC load modulation amplitude limits of classes 2 to 6 are less strict than the previous PICC limit in ISO/IEC 14443-2:2010.

NOTE 2 For "Class 4", "Class 5" and "Class 6" PICCs, the use of test PCD assembly 2 increases the measured values of load modulation by a factor of approximately 2 compared with test PCD assembly 1.

Figure 11 to 15 are illustrations of the PCD and PICC load modulation amplitude limits for each class.

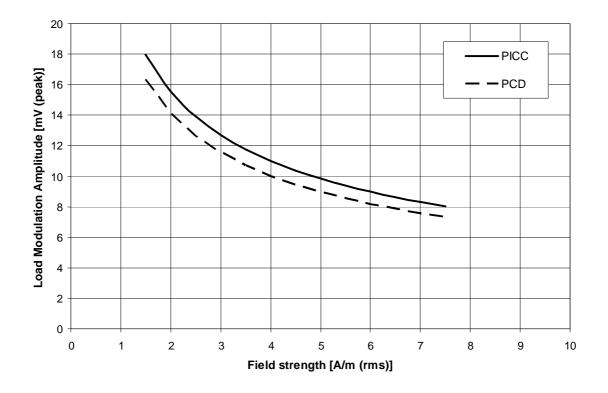


Figure 11 — Load modulation amplitude limits for "Class 1"

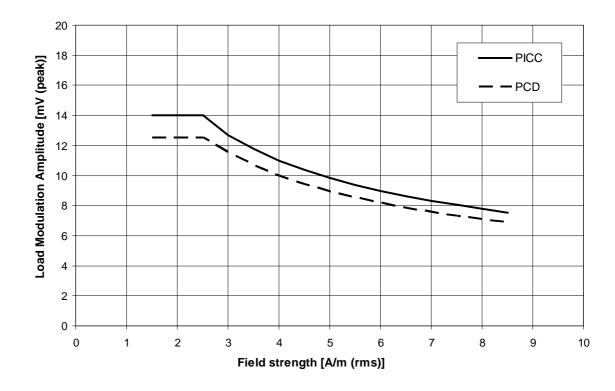


Figure 12 — Load modulation amplitude limits for "Class 2" and "Class 3"

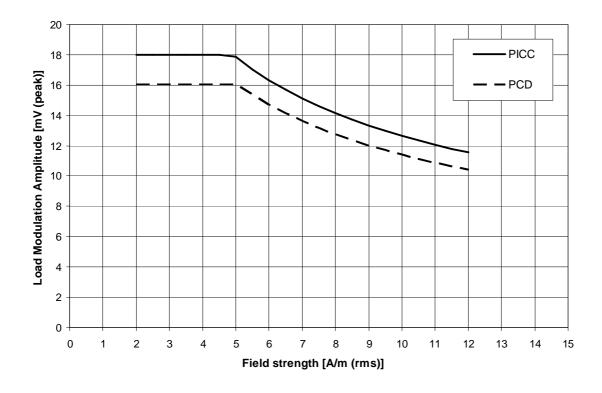


Figure 13 — Load modulation amplitude limits for "Class 4"

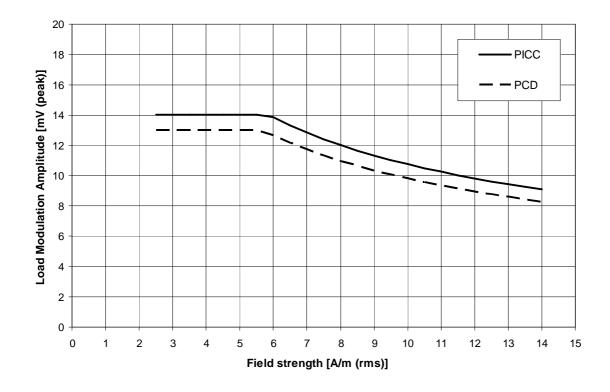


Figure 14 — Load modulation amplitude limits for "Class 5"

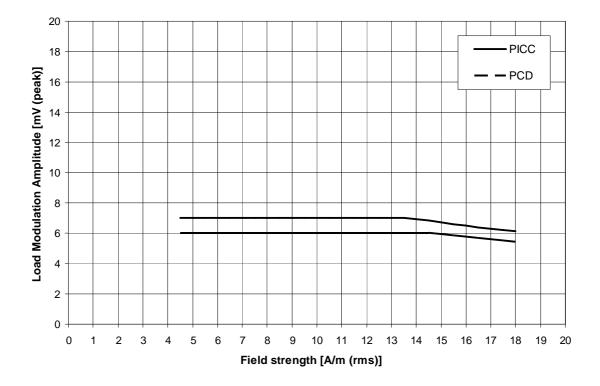


Figure 15 — Load modulation amplitude limits for "Class 6"